

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/774,788	SHIN ET AL.	
	<b>Examiner</b>	Art Unit	
	Patrick J. Lee	2878	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Consulted w/ S. Allen	5/17/2005	PL
East (See attached)	5/18/2005	PL
East (See attached)	5/19/2005	PL
East (See attached)	9/19/2005	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	11/17/2005	PL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
250	227.18	11/17/2005	PL